Fault-Tolerant Architectures and Applications for Embedded and Reconfigurable Systems-on-a-Chip

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Deadline for manuscript submissions:
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Message from the Guest Editors

With the increasing dependability of computing system in everyday life, such as in automotive and industrial industries, scientific experiments, and space missions, it is important to have systems that guarantee reliability and are capable of operating, even in harsh conditions, as reliability has a direct impact on a systems's performance. The aim of this Special Issue is to gather the most recent developments and applications of embedded and reconfigurable systems, covering, but not limited to, the following scopes:

- Applications of fault-tolerance mechanisms in embedded and reconfigurable (SoC-FPGA) systems, e.g., neural networks, edge computing, and automotive and space systems
- Approximating computing architectures
- Fault-tolerance methods for heterogeneous systems
- Communication mechanisms for inter-layer fault-tolerance stack
- Unified hardware–software fault-tolerance
- Systems with limited resources: low-power and portable systems
- Open source implementations
- EDA tools.

Welcome to contribute.

Special Issue

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Message from the Editor-in-Chief

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